



AO4722

N-Channel Enhancement Mode Field Effect Transistor

SRFET™

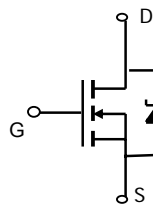
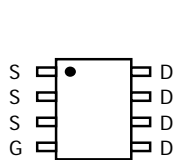
General Description

SRFET™ The AO4722 uses advanced trench technology with a monolithically integrated Schottky diode to provide excellent $R_{DS(ON)}$, and low gate charge. This device is suitable for use as a low side FET in SMPS, load switching and general purpose applications. *Standard Product AO4722 is Pb-free (meets ROHS & Sony 259 specifications).*

Features

- V_{DS} (V) = 30V
- I_D = 11.6A (V_{GS} = 10V)
- $R_{DS(ON)}$ < 14m Ω (V_{GS} = 10V)
- $R_{DS(ON)}$ < 22m Ω (V_{GS} = 4.5V)

UIS TESTED!
Rg, Ciss, Coss, Crss Tested



SRFET™

Soft Recovery MOSFET:
Integrated Schottky Diode

Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

| Parameter | Symbol | 10 Sec | Steady State | Units | |
|--|----------------|------------------------|--------------|------------------|---|
| Drain-Source Voltage | V_{DS} | 30 | | V | |
| Gate-Source Voltage | V_{GS} | ± 20 | | | |
| Continuous Drain Current ^A | I_{DSM} | $T_A=25^\circ\text{C}$ | 11.6 | 8.5 | A |
| | | $T_A=70^\circ\text{C}$ | 9.3 | 6.8 | |
| Pulsed Drain Current ^B | I_{DM} | 100 | | | |
| Avalanche Current ^B | I_{AR} | 17 | | | |
| Repetitive avalanche energy $L=0.3\text{mH}^B$ | E_{AR} | 43 | | mJ | |
| Power Dissipation | P_{DSM} | $T_A=25^\circ\text{C}$ | 3.1 | 1.7 | W |
| | | $T_A=70^\circ\text{C}$ | 2.0 | 1.1 | |
| Junction and Storage Temperature Range | T_J, T_{STG} | -55 to 150 | | $^\circ\text{C}$ | |

Thermal Characteristics

| Parameter | Symbol | Typ | Max | Units |
|--|-----------------|--------------|-----|--------------------|
| Maximum Junction-to-Ambient ^A | $R_{\theta JA}$ | 32 | 40 | $^\circ\text{C/W}$ |
| Maximum Junction-to-Ambient ^A | | Steady-State | 60 | 75 |
| Maximum Junction-to-Lead ^C | $R_{\theta JL}$ | 17 | 24 | $^\circ\text{C/W}$ |

Electrical Characteristics (T_J=25°C unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|-----------------------------|--|---|-----|------|------|-------|
| STATIC PARAMETERS | | | | | | |
| BV _{DSS} | Drain-Source Breakdown Voltage | I _D =250μA, V _{GS} =0V | 30 | | | V |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} =30V, V _{GS} =0V | | | 0.1 | mA |
| | | T _J =125°C | | | 10 | |
| I _{GSS} | Gate-Body leakage current | V _{DS} =0V, V _{GS} = ±20V | | | 0.1 | μA |
| V _{GS(th)} | Gate Threshold Voltage | V _{DS} =V _{GS} , I _D =250μA | 1.3 | 1.65 | 2.5 | V |
| I _{D(ON)} | On state drain current | V _{GS} =10V, V _{DS} =5V | 100 | | | A |
| R _{DS(ON)} | Static Drain-Source On-Resistance | V _{GS} =10V, I _D =11.6A | | 11.5 | 14 | mΩ |
| | | T _J =125°C | | 17 | 21 | |
| | | V _{GS} =4.5V, I _D =9.3A | | 17.5 | 22 | mΩ |
| g _{FS} | Forward Transconductance | V _{DS} =5V, I _D =11.6A | | 28 | | S |
| V _{SD} | Diode Forward Voltage | I _S =1A, V _{GS} =0V | | 0.43 | 0.5 | V |
| I _S | Maximum Body-Diode + Schottky Continuous Current | | | | 4 | A |
| DYNAMIC PARAMETERS | | | | | | |
| C _{iss} | Input Capacitance | V _{GS} =0V, V _{DS} =15V, f=1MHz | | 903 | 1100 | pF |
| C _{oss} | Output Capacitance | | | 225 | | pF |
| C _{rss} | Reverse Transfer Capacitance | | | 91 | | pF |
| R _g | Gate resistance | V _{GS} =0V, V _{DS} =0V, f=1MHz | | 1.7 | 2.6 | Ω |
| SWITCHING PARAMETERS | | | | | | |
| Q _g (10V) | Total Gate Charge | V _{GS} =10V, V _{DS} =15V, I _D =11.6A | | 15.3 | 20 | nC |
| Q _g (4.5V) | Total Gate Charge | | | 7.8 | 10 | nC |
| Q _{gs} | Gate Source Charge | | | 2.0 | | nC |
| Q _{gd} | Gate Drain Charge | | | 3.9 | | nC |
| t _{D(on)} | Turn-On DelayTime | V _{GS} =10V, V _{DS} =15V, R _L =1.3Ω, R _{GEN} =3Ω | | 5.0 | | ns |
| t _r | Turn-On Rise Time | | | 9.2 | | ns |
| t _{D(off)} | Turn-Off DelayTime | | | 17.8 | | ns |
| t _f | Turn-Off Fall Time | | | 4.4 | | ns |
| t _{rr} | Body Diode Reverse Recovery Time | I _F =11.6A, dI/dt=300A/μs | | 17 | 20 | ns |
| Q _{rr} | Body Diode Reverse Recovery Charge | I _F =11.6A, dI/dt=300A/μs | | 30.0 | | nC |

A: The value of R_{θJA} is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature.

C: The R_{θJA} is the sum of the thermal impedance from junction to lead R_{θJL} and lead to ambient.

D: The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The SOA curve provides a single pulse rating.

F: The current rating is based on the t ≤ 10s junction to ambient thermal resistance rating.

Rev1: May. 2007

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

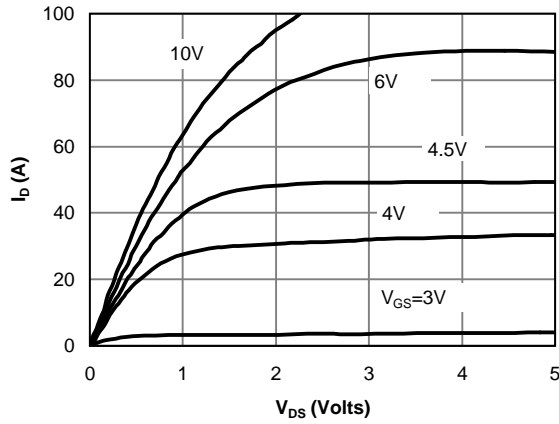


Figure 1: On-Region Characteristics

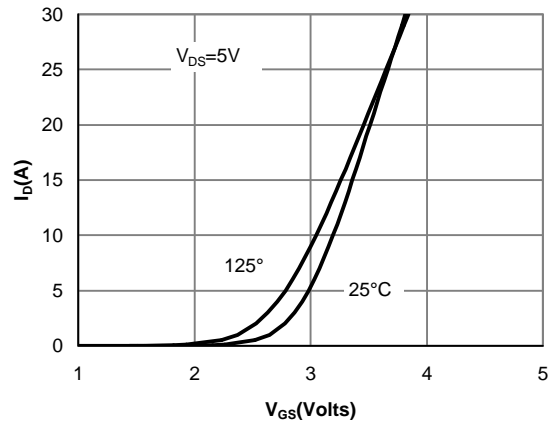


Figure 2: Transfer Characteristics

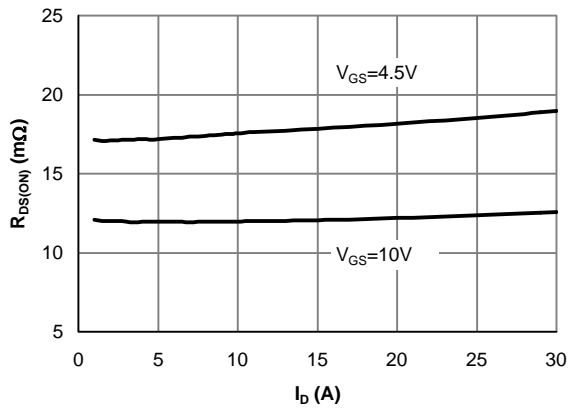


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

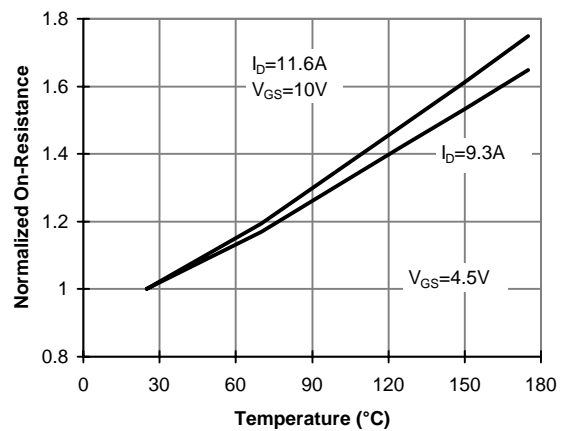


Figure 4: On-Resistance vs. Junction Temperature

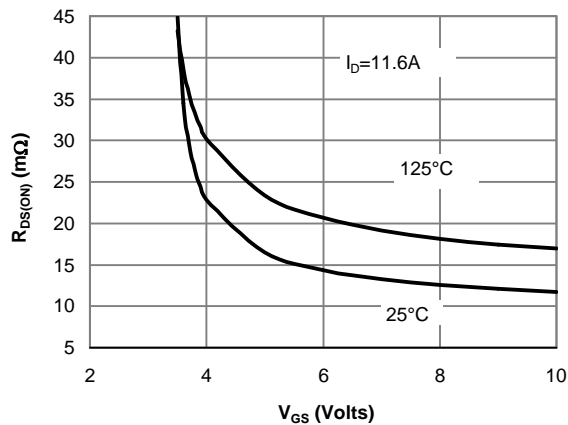


Figure 5: On-Resistance vs. Gate-Source Voltage

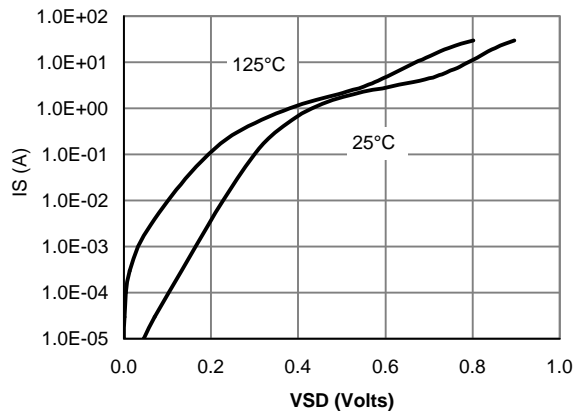


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

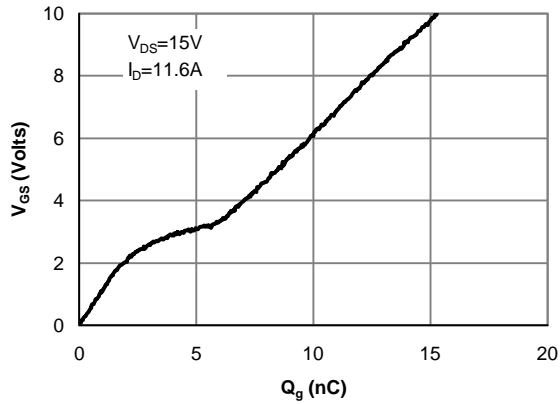


Figure 7: Gate-Charge Characteristics

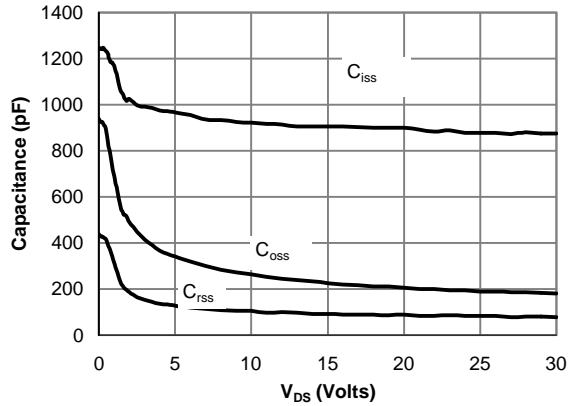


Figure 8: Capacitance Characteristics

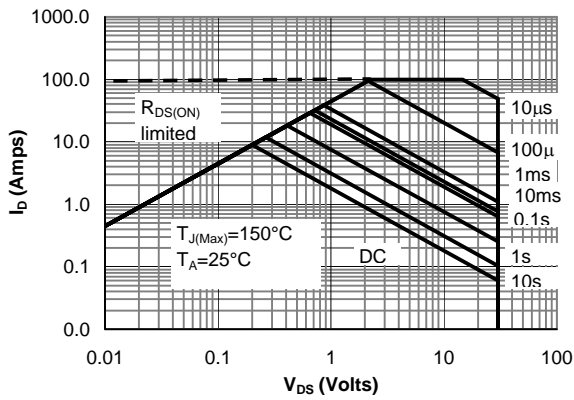


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

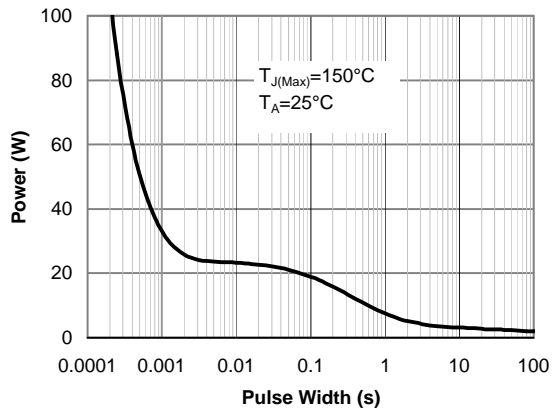


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

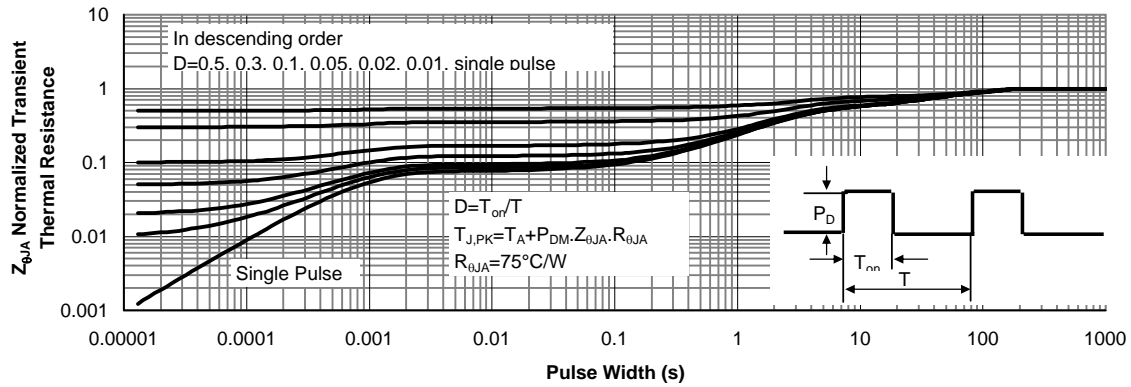


Figure 11: Normalized Maximum Transient Thermal Impedance (Note E)